

# Analysis Tech 32-102 Event Detector

## DESCRIPTION:

Used for reliability/life testing of electrical connectors. Also applicable to testing of passive interconnects such as surface mount solder joints and chip-to-carrier interconnect systems.

- 32 channels with simultaneous monitoring
- Channel test current settings  
10, 20, 50, 100 ma
- Channel current source tolerance (0-20  $\Omega$  load)  
+4%, -11%
- Threshold voltage tolerance (pulse duration)  
 $\pm 5\%$  (typical),  $\pm 10\%$  (maximum)
- Selectable minimum event duration settings  
0.1, 0.5, 1.0  $\mu\text{s}$
- Data collection via RS232C serial port
- Compatible with HLV amplifiers to provide low level threshold resistance and low current test capabilities



## LOCATION: IEEC RELIABILITY LAB

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# CONTACTS

For more information or to arrange for the use of this equipment, contact any of the IEEC staff members listed below:

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